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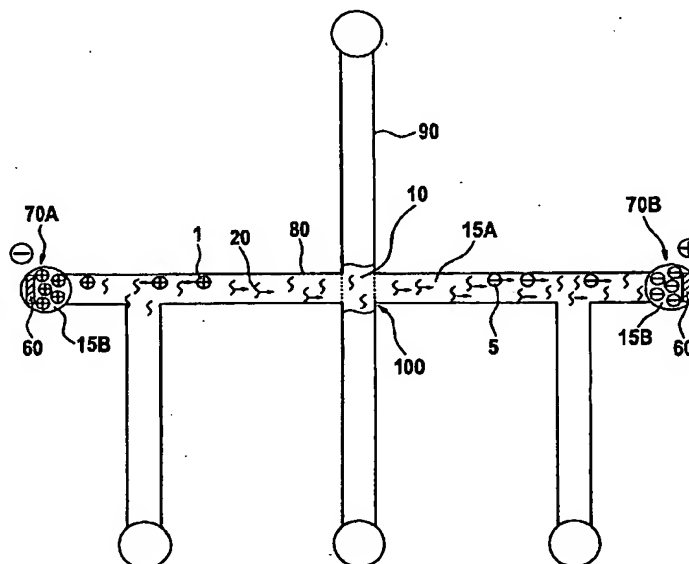
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(54) Title: CHARGED PARTICLE REDUCTION IN ANALYTE PROCESSING



(57) **Abstract:** The invention discloses a method for processing analytes (20) in a first solution (15A) also containing charged parti-
cles (1, 5), the first solution being in a compartment, comprising the method steps of subjecting said compartment to an electric field,
thereby reducing the amount of the charged particles (1, 5) in a part (10) of the first solution 15A, which is located in a section of the
compartment, and subjecting said part (10) of the first solution obtained in step A) containing the analytes (20) to further processing.

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